

Defect oriented fault coverage of 100stuck-at fault test sets

Blyzniuk, M.; Cibakova, Tatiana; Gramatova, Elena; Kuzmich, W.; Lobur, M.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** Proceedings of the 7th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2000 : Gdynia, Poland, 15-17 June 2000 2000 / p. 511-516 : ill <https://repo.pw.edu.pl/info/seam?ps=20&id=WUT7e20f35d67ae45d3b2d1264d7a4ba722&en&pn=1&cid=156607>

Hierarchical defect level test quality analysis

Blyzniuk, M.; Cibakova, Tatiana; Gramatova, Elena; Kuzmich, W.; Lobur, M.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** VILAB User Forum 2000 / [11] p

Hierarchical defect-oriented fault simulation for digital circuits

Blyzniuk, M.; Cibakova, Tatiana; Gramatova, Elena; Kuzmich, W.; Lobur, M.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** IEEE European Test Workshop : 23-26 May 2000, Cascais, Portugal : ETW 2000 : proceedings 2000 / p. 69-74 : ill <https://ieeexplore.ieee.org/document/873781>

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Probabilistic analysis of CMOS physical defects in VLSI circuits for test coverage improvement

Blyzniuk, M.; Kazyrya, I.; Kuzmich, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** Microelectronics reliability 2001 / p. 2023-2040 : ill <https://www.sciencedirect.com/science/article/pii/S0026271401000920>